



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Satoshi Murakami, et al. Art Unit : 2814
Serial No. : 10/006,043 Examiner : Nathan W. Ha
Filed : December 4, 2001
Title : SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE
SAME

MAIL STOP RCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

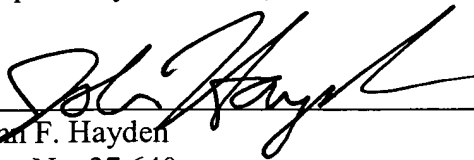
Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AL	JAPAN 2000-332256 – English Abstract: DIALOG(R)File 347: JAPIO (2005); Accession No. 06746401 and family to U.S. Patent No. 6,306,694 (Desig. ID “AA”), U.S. Patent No. 6,737,304 (Desig. ID “AB”), U.S. Patent Application Publication No. 2002/0028543 (Desig. ID “AC”) and U.S. Patent Application Publication No. 2004/0197971 (Desig. ID “AD”).

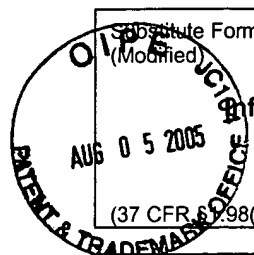
This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date: 8/5/05


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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-289001	Application No. 10/006,043
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))		Applicant Satoshi Murakami, et al.	
		Filing Date December 4, 2001	Group Art Unit 2814

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,306,694 B1	10/23/2001	Yamazaki et al.			03/10/2000
	AB	6,737,304 B2	05/18/2004	Yamazaki et al.			10/10/2001
	AC	2002/0028543 A1	03/07/2002	Yamazaki et al.			10/10/2001
	AD	2004/0197971 A1	10/07/2004	Yamazaki et al.			04/26/2004
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	2000-332256	11/30/2000	JAPAN			AB	
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	